



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... 09/653,149  
Filing Date ..... August 31, 2000  
Inventor ..... Garo J. Derderian, et al.  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2818  
Examiner ..... T. Lee  
Attorney's Docket No. .... MI22-1330  
Title: Capacitor Fabrication Methods Including Forming a Conductive Layer

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

To: Commissioner for Patents  
PO Box 1450  
Art Unit 2818  
Alexandria, VA 22313-1450

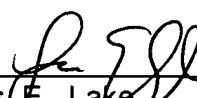
From: James E. Lake (Tel. 509-624-4276; Fax 509-838-3424)  
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601 W. First Avenue, Suite 1300  
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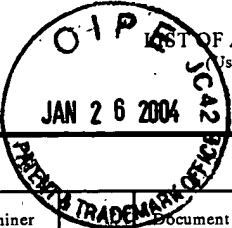
In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art. Citation of these references is respectfully requested.

This Supplemental Information Disclosure Statement is being filed after the filing of the Request for Continued Examination (RCE) Application and before receipt of the first Office Action. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee.

Respectfully submitted,

Dated: 26 Jan 2004

By:   
James E. Lake  
Reg. No. 44,854

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1330	SERIAL NO. 09/653,149	
				APPLICANT    Garo J. Derderian		
				FILING DATE August 31, 2000	GROUP 2812	
U.S. PATENT DOCUMENTS						
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA    6,162,712	12/00	Baum			
	AB    6,018,065	01/00	Baum			
	AC    6,281,543	08/01	Al-Shareef et al			
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
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FOREIGN PATENT DOCUMENTS						
	Document Number	Date	Country	Class	Subclass	Translation
						Yes    No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
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	AQ					
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<p><small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small></p>						